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<u>L3</u>	L2 and l1	11	<u>L3</u>
<u>L2</u>	717/130,136,139,140.ccls.	585	<u>L2</u>
<u>L1</u>	profile and execute and translation and physical and logical and record\$	821	<u>L1</u>

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L23	L22 and l10	0	L23
L22	717/136,137,138,139,140.ccls.	545	L22
L21	L20 and l10	0	L21
L20	717/127,128,129,130,131,132,133,134,135.ccls.	748	L20
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L19	profil\$ near8 (distinc\$ or differ\$ or separat\$) near9 (address\$ near5 (translat\$ or conver\$))	2	L19
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L18	profile\$ near4 address\$ near4 (conver\$ or transfer\$ or trnaslat\$)	0	L18
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L17	profile\$ near4 address\$ near4 (conver\$ or transfer\$ or trnaslat\$)	1	L17
<i>DB=JPAB; PLUR=YES; OP=ADJ</i>			

<u>L16</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or tnaslat\$)	1	<u>L16</u>
<i>DB=EPAB; PLUR=YES; OP=ADJ</i>		
<u>L15</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or tnaslat\$)	0	<u>L15</u>
<i>DB=USOC; PLUR=YES; OP=ADJ</i>		
<u>L14</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or tnaslat\$)	0	<u>L14</u>
<i>DB=PGPB; PLUR=YES; OP=ADJ</i>		
<u>L13</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or tnaslat\$) and (pyhsical\$ near5 address\$)	0	<u>L13</u>
<i>DB=USPT; PLUR=YES; OP=ADJ</i>		
<u>L12</u> L10 and logical\$	7	<u>L12</u>
<u>L11</u> L10 and (pyhsical\$ near5 address\$)	0	<u>L11</u>
<u>L10</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or tnaslat\$)	13	<u>L10</u>
<u>L9</u> profile\$ near4 (distinc\$ or differ\$) near8 address\$ near4 (trans\$ or conver\$)	0	<u>L9</u>
<u>L8</u> l6 and (translat\$ near4 address\$)	1	<u>L8</u>
<u>L7</u> L6 and (profil\$ or address\$)	1	<u>L7</u>
<u>L6</u> 6047363.pn.	1	<u>L6</u>
<u>L5</u> l3 and (address\$ near5 translat\$)	0	<u>L5</u>
<u>L4</u> L3 and profil\$ and address\$	0	<u>L4</u>
<u>L3</u> 6043363.PN.	1	<u>L3</u>
<u>L2</u> 6763452.pn.	0	<u>L2</u>
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*Richardson, K.J.; Flynn, M.J.;*

System Sciences, 1992. Proceedings of the Twenty-Fifth Hawaii International Conference on , Volume: i , 7-10 Jan. 1992

Pages:58 - 66 vol.1

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